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January 2008

74LVTH125 Low Voltage Quad Buffer with 3-STATE Outputs

Features

- Input and output interface capability to systems at 5V V_{CC}
- Bushold data inputs eliminate the need for external pull-up resistors to hold unused inputs
- Live insertion/extraction permitted
- Power Up/Down high impedance provides glitch-free bus loading
- Outputs source/sink –32mA/+64mA
- Functionally compatible with the 74 series 125
- Latch-up performance exceeds 500mA
- ESD performance:
 - Human-body model > 2000V
 - Machine model > 200V

Ordering Information

- Charged-device model > 1000V

General Description

The LVTH125 contains four independent non-inverting buffers with 3-STATE outputs.

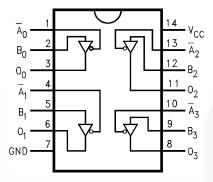
These buffers are designed for low-voltage (3.3V) V_{CC} applications, but with the capability to provide a TTL interface to a 5V environment. The LVTH125 is fabricated with an advanced BiCMOS technology to achieve high speed operation similar to 5V ABT while maintaining a low power dissipation.

	mation	
Order Number	Package Number	Package Description
74LVTH125M	M14A	14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150" Narrow
74LVTH125SJ	M14D	14-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74LVTH125MTC	MTC14	14-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide

Device also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering number.

All packages are lead free per JEDEC: J-STD-020B standard.

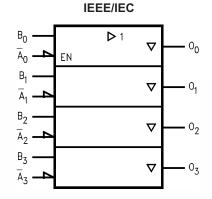
Connection Diagram



Pin Description

Pin Names	Description
Ā _n , B _n	Inputs
O _n	3-STATE Outputs

Logic Symbol



Truth Table

Inp	uts	Output
Ā _n	B _n	O _n
L	L	L
L	Н	Н
Н	Х	Z

H = HIGH Voltage Level

L = LOW Voltage Level

X = Immaterial

Z = HIGH Impedance

Absolute Maximum Ratings

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only.

Symbol	Parameter	Rating
V _{CC}	Supply Voltage	-0.5V to +4.6V
VI	DC Input Voltage	-0.5V to +7.0V
Vo	DC Output Voltage	
	Output in 3-STATE	-0.5V to +7.0V
	Output in HIGH or LOW State ⁽¹⁾	-0.5V to +7.0V
I _{IK}	DC Input Diode Current, V _I < GND	–50mA
I _{ОК}	DC Output Diode Current, V _O < GND	–50mA
Ι _Ο	DC Output Current, $V_O > V_{CC}$	
	Output at HIGH State	64mA
	Output at LOW State	128mA
I _{CC}	DC Supply Current per Supply Pin	±64mA
I _{GND}	DC Ground Current per Ground Pin	±128mA
T _{STG}	Storage Temperature	–65°C to +150°C

Note:

1. I_O Absolute Maximum Rating must be observed.

Recommended Operating Conditions

The Recommended Operating Conditions table defines the conditions for actual device operation. Recommended operating conditions are specified to ensure optimal performance to the datasheet specifications. Fairchild does not recommend exceeding them or designing to absolute maximum ratings.

Symbol	Parameter	Min	Max	Units
V _{CC}	Supply Voltage	2.7	3.6	V
VI	Input Voltage	0	5.5	V
I _{OH}	HIGH-Level Output Current		-32	mA
I _{OL}	LOW-Level Output Current		64	mA
T _A	Free-Air Operating Temperature	-40	85	°C
$\Delta t / \Delta V$	Input Edge Rate, $V_{IN} = 0.8V - 2.0V$, $V_{CC} = 3.0V$	0	10	ns/V

					$T_A = -4$	0°C to +	85°C	
					Min.	Typ. ⁽²⁾	Max.	1
Symbol	Parameter		V _{CC} (V)	Conditions				Units
V _{IK}	Input Clamp Diode Volta	ige	2.7	I _I = -18mA			-1.2	V
VIH	Input HIGH Voltage		2.7–3.6	$V_0 \le 0.1V$ or	2.0			V
VIL	Input LOW Voltage		2.7–3.6	$V_{O} \ge V_{CC} - 0.1V$			0.8	V
V _{OH}	Output HIGH Voltage		2.7–3.6	I _{OH} = -100μA	V _{CC} - 0.2			V
		-	2.7	I _{OH} = -8mA	2.4			
		-	3.0	$I_{OH} = -32 \text{mA}$	2.0			1
V _{OL}	Output LOW Voltage		2.7	I _{OL} = 100μA			0.2	V
				$I_{OL} = 24 \text{mA}$			0.5	
			3.0	$I_{OL} = 16 \text{mA}$			0.4	1
				$I_{OL} = 32 \text{mA}$			0.5	
				$I_{OL} = 64 \text{mA}$			0.55	
I _{I(HOLD)}	Bushold Input Minimum	Drive	3.0	$V_{I} = 0.8V$	75			μA
				$V_{I} = 2.0V$	-75			
I _{I(OD)}	Bushold Input Over-Drive Current to Change State		3.0	(3)	500			μA
. ,				(4)	-500			
lı	Input Current		3.6	$V_{I} = 5.5V$			10	μA
	Con	trol Pins	3.6	$V_{I} = 0V \text{ or } V_{CC}$			±1	1
	Data	Pins	3.6	$V_I = 0V$			-5	1
				$V_I = V_{CC}$			1	
I _{OFF}	Power Off Leakage Cur	rent	0	$0V \le V_I \text{ or } V_O \le 5.5V$			±100	μA
I _{PU/PD}	Power up/down 3-STATI Output Current	Ξ	0–1.5	$V_0 = 0.5V$ to 3.0V, $V_1 = GND$ or V_{CC}			±100	μA
I _{OZL}	3-STATE Output Leakag	e Current	3.6	$V_{O} = 0.5V$			-5	μA
I _{OZH}	3-STATE Output Leakag	e Current	3.6	$V_0 = 3.0V$			5	μA
I _{OZH} +	3-STATE Output Leakag	e Current	3.6	$V_{CC} < V_O \le 5.5V$			10	μA
I _{CCH}	Power Supply Current		3.6	Outputs HIGH			0.19	mA
I _{CCL}	Power Supply Current		3.6	Outputs LOW			5	mA
I _{CCZ}	Power Supply Current		3.6	Outputs Disabled			0.19	mA
I _{CCZ} +	Power Supply Current		3.6	$V_{CC} \le V_O \le 5.5V$, Outputs Disabled			0.19	mA
ΔI_{CC}	Increase in Power Supp Current ⁽⁵⁾	ly	3.6	One Input at $V_{CC} - 0.6V$, Other Inputs at V_{CC} or GND			0.2	mA

74LVTH125 — Low Voltage Quad Buffer with 3-STATE Outputs

Notes:

2. All typical values are at V_{CC} = 3.3V, $T_A = 25^{\circ}C$.

3. An external driver must source at least the specified current to switch from LOW-to-HIGH.

4. An external driver must sink at least the specified current to switch from HIGH-to-LOW.

5. This is the increase in supply current for each input that is at the specified voltage level rather than V_{CC} or GND.

Dynamic Switching Characteristics(6)

			Conditions	-	Γ _A = 25°C)	
Symbol	Parameter	V _{CC} (V)	$C_L = 50 \text{ pF, } R_L = 500\Omega$	Min.	Тур.	Max.	Units
V _{OLP}	Quiet Output Maximum Dynamic V _{OL}	3.3	(7)		0.8		V
V _{OLV}	Quiet Output Minimum Dynamic V _{OL}	3.3	(7)		-0.8		V

Notes:

6. Characterized in SOIC package. Guaranteed parameter, but not tested.

7. Max number of outputs defined as (n). n-1 data inputs are driven 0V to 3V. Output under test held LOW.

AC Electrical Characteristics

		$\label{eq:TA} \begin{split} \textbf{T}_{\textbf{A}} = -\textbf{40}^{\circ}\textbf{C} \text{ to } \textbf{+85}^{\circ}\textbf{C},\\ \textbf{C}_{\textbf{L}} = \textbf{50}\textbf{pF}, \ \textbf{R}_{\textbf{L}} = \textbf{500}\Omega \end{split}$					
		Vcc	₂ = 3.3V ± 0).3V	V _{CC} =	= 2.7V	
Symbol	Parameter	Min.	Typ. ⁽⁸⁾	Max.	Min.	Max.	Units
t _{PLH}	Propagation Delay, Data to Output	1.0		3.5	1.0	4.5	ns
t _{PHL}	1	1.0		3.9	1.0	4.9	
t _{PZH}	Output Enable Time	1.0		4.0	1.0	5.5	ns
t _{PZL}	1	1.1		4.0	1.1	5.4	
t _{PHZ}	Output Disable Time	1.5		4.5	1.5	5.7	ns
t _{PLZ}	1	1.3		4.5	1.3	4.0	
t _{OSHL} , t _{OSLH}	Output to Output Skew ⁽⁹⁾			1.0		1.0	ns

Notes:

8. All typical values are at $V_{CC} = 3.3V$, $T_A = 25^{\circ}C$.

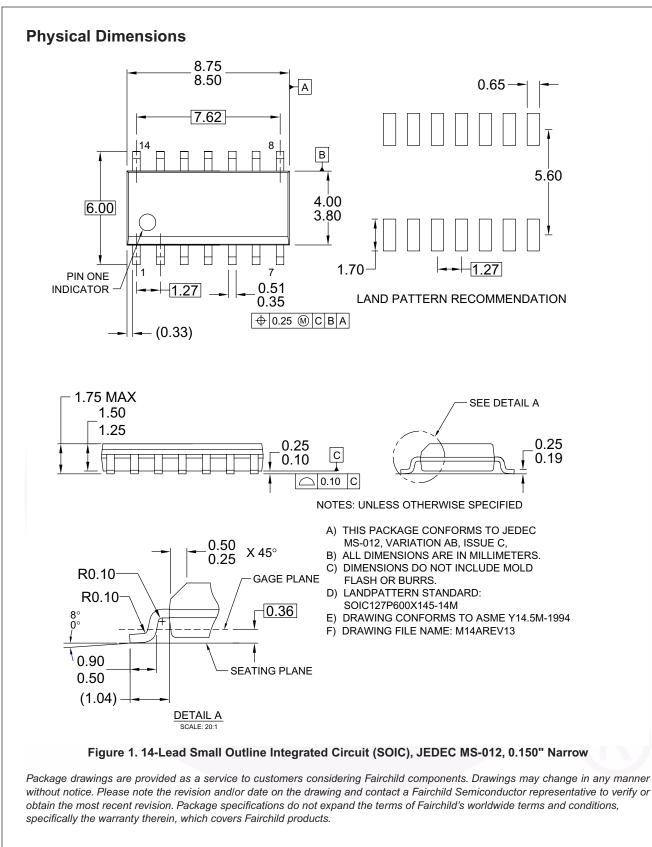
 Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the same direction, either HIGH-to-LOW (t_{OSHL}) or LOW-to-HIGH (t_{OSLH}).

Capacitance⁽¹⁰⁾

Symbol	Parameter	Conditions	Typical	Units
C _{IN}	Input Capacitance	$V_{CC} = 0V, V_I = 0V \text{ or } V_{CC}$	4	pF
C _{OUT}	Output Capacitance	V_{CC} = 3.0V, V_{O} = 0V or V_{CC}	8	pF

Note:

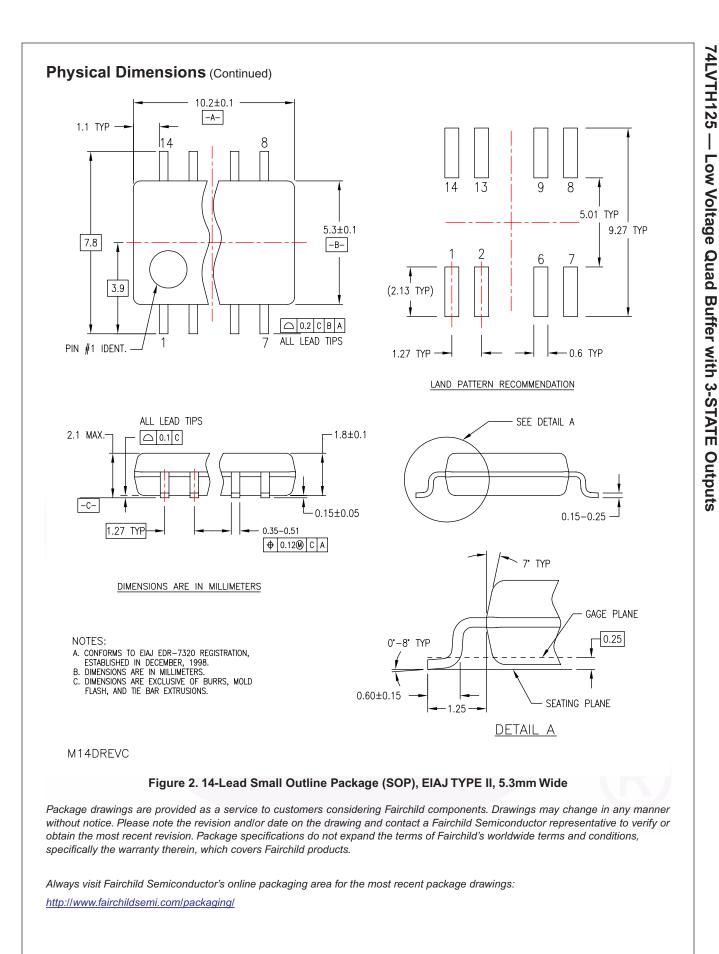
10. Capacitance is measured at frequency f = 1MHz, per MIL-STD-883B, Method 3012.

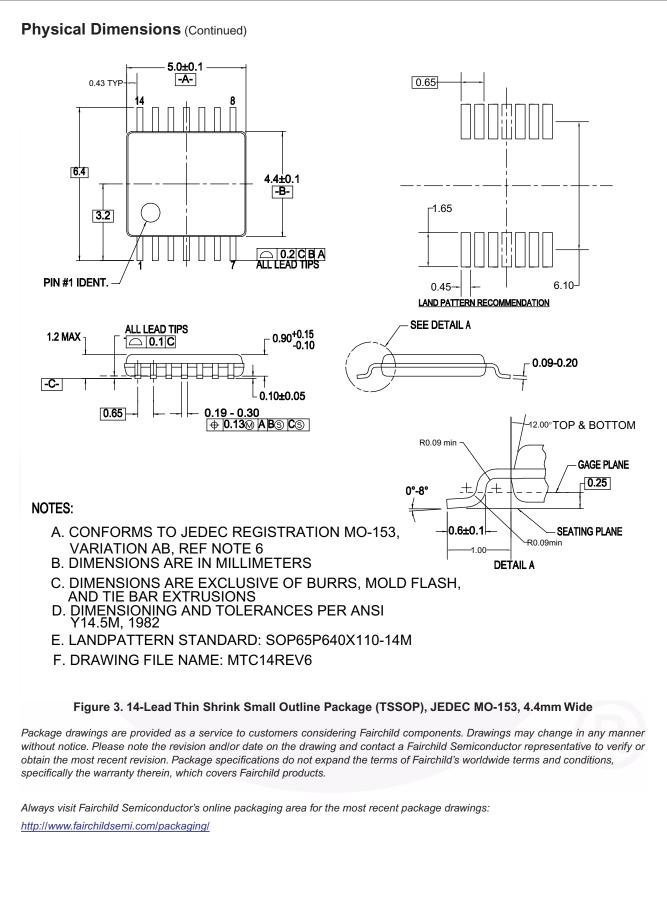


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